

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination BAEK ET AL.	
		Examiner Leslie J. Evanisko	Art Unit 2854	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-2002/0109799	08-2002	Choi et al.	349/43
	B	US-2003/0084796	05-2003	Kwon et al.	101/41
	C	US-2004/0119935	06-2004	Baek et al.	349/187
	D	US-			
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	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

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